

STF6N62K3, STFI6N62K3, STI6N62K3, STP6N62K3, STU6N62K3

N-channel 620 V, 0.95 Ωtyp., 5.5 A SuperMESH3[™] Power MOSFET in TO-220FP, I²PAKFP, I²PAK, TO-220, IPAK packages

Features

Order codes	V_{DSS}	R _{DS(on)} max.	I _D	P _{TOT}
STF6N62K3				30 W
STFI6N62K3				30 W
STI6N62K3	620 V	< 1.2 Ω	5.5 A	90 W
STP6N62K3				90 W
STU6N62K3				90 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitance
- Improved diode reverse recovery characteristics
- Zener-protected

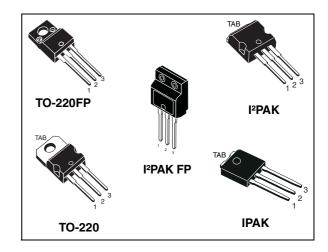
Applications

Switching applications

Description

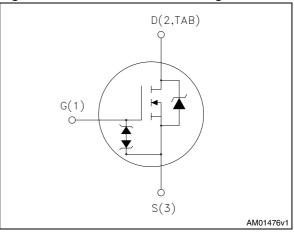
These SuperMESH3[™] Power MOSFETs are the result of improvements applied to STMicroelectronics' SuperMESH[™] technology, combined with a new optimized vertical structure. These devices boast an extremely low onresistance, superior dynamic performance and high avalanche capability, rendering them suitable for the most demanding applications.

Table 1.	Device summary
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Datasheet – production data

Figure 1. Internal schematic diagram



Order codes	Marking	Package	Packaging
STF6N62K3		TO-220FP	
STFI6N62K3		I ² PAKFP	
STI6N62K3	6N62K3	I ² PAK	Tube
STP6N62K3		TO-220	
STU6N62K3		IPAK	

August 2012

Doc ID 14676 Rev 4

1/19

This is information on a product in full production.

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2	Electrical characteristics
	2.1 Electrical characteristics (curves)
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1 Electrical ratings

Symbol	Parameter	TO-220FP I ² PAKFP	I ² PAK TO-220	IPAK	Unit		
V_{DS}	Drain-source voltage		620		V		
V _{GS}	Gate- source voltage		± 30		V		
I _D	Drain current (continuous) at T _C = 25 °C	5.5 ⁽¹⁾	5.5		Α		
I _D	Drain current (continuous) at T _C = 100 °C	3 (1)	3		Α		
I _{DM} ⁽²⁾	Drain current (pulsed)	22 (1)	22		22		Α
P _{TOT}	Total dissipation at $T_{C} = 25 \text{ °C}$	30	90		W		
I _{AR} ⁽³⁾	Avalanche current, repetitive or not-repetitive		5.5		Α		
E _{AS} ⁽⁴⁾	Single pulse avalanche energy		140		mJ		
ESD	Gate-source human body model (R=1.5 kΩ C=100 pF)		2.5		kV		
dv/dt ⁽⁵⁾	Peak diode recovery voltage slope		12		V/ns		
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; Tc = 25 °C)	2500	2500		v		
T _{stg}	Storage temperature	-5	5 to 150		°C		
Тj	Max. operating junction temperature		150				

Table 2. Absolute maximum ratings

1. Limited by maximum junction temperature.

2. Pulse width limited by safe operating area.

3. Pulse width limited by Tj max.

4. Starting Tj = 25 °C, $I_D = I_{AR}$, $V_{DD} = 50$ V.

5. $I_{SD} \leq 5.5$ A, di/dt ≤ 400 A/µs, $V_{DD} = 80\% V_{(BR)DSS}$, $V_{DSpeak} \leq V_{(BR)DSS}$.

Table 3. Thermal data

Symbol	Parameter	TO-220FP I ² PAKFP	I²PAK TO-220	IPAK	Unit
R _{thj-case}	Thermal resistance junction-case max.	4.17	1.39		°C/W
R _{thj-amb}	Thermal resistance junction-ambient max.	62.5		100	°C/W



2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 1 \text{ mA}, V_{GS} = 0$	620			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 620 V V _{DS} = 620 V, T _C =125 °C			0.8 50	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20 V			± 9	μA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50 \ \mu A$	3	3.75	4.5	V
R _{DS(on}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 2.8 A		0.95	1.2	Ω

Table 4. On /off states

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 50 V, f = 1 MHz, V _{GS} = 0	-	875 100 17	-	pF pF pF
C _{oss(er)} ⁽¹⁾	Equivalent output capacitance energy related	$V_{GS} = 0, V_{DS} = 0$ to 480 V	-	28	-	pF
C _{oss(tr)} ⁽²⁾	Equivalent output capacitance time related		-	63	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	3.5	-	Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 496 \text{ V}, I_D = 5.5 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 20</i>)	-	34 4 22	-	nC nC nC

1. Is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

2. Is defined as a constant equivalent capacitance giving the same storage energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



	•••••••					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD} = 310 \text{ V}, I_D = 2.75 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 19</i>)	-	22 12 49 20	-	ns ns ns ns

Table 6. Switching times

Table 7.Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		5.5 27	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 5.5 \text{ A}, V_{GS} = 0$	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 5.5 A, di/dt = 100 A/μs V _{DD} = 60 V (see <i>Figure 24</i>)	-	290 1.9 13.5		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 5.5 A, di/dt = 100 A/μs V _{DD} = 60 V, T _j = 150 °C (see <i>Figure 24</i>)	-	335 2.4 14.5		ns μC Α

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = 300 µs, duty cycle 1.5%

Table 8.	Gate-source	Zener	diode

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
`		Gate-source breakdown voltage (I _D = 0)	lgs=± 1 mA	30		-	V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components



lр

2.1 **Electrical characteristics (curves)**

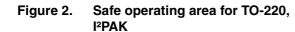


Figure 3. Thermal impedance for TO-220,

0.2

0.1

0.05

0.02



 $Z_{th} = k R_{thJ-c}$

 $10^{-1} t_{p}(s)$

 $\delta = t_p / \tau$

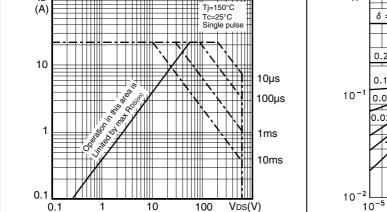
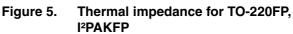


Figure 4. Safe operating area for TO-220FP, **I**²**PAKFP**

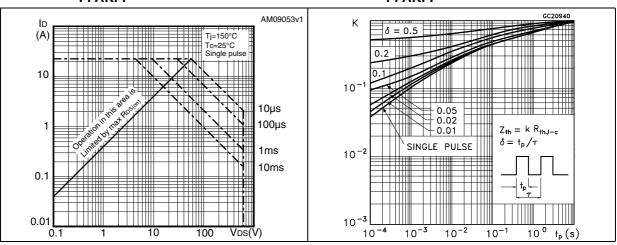


10⁻²

 10^{-3}

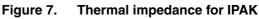
0.01 SINGLE PULSE

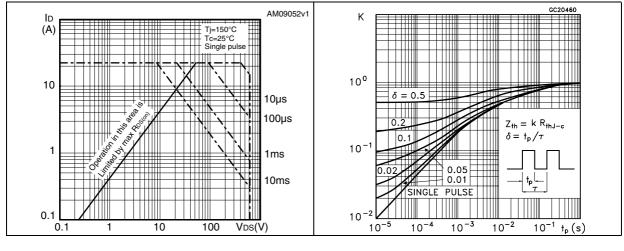
 10^{-4}



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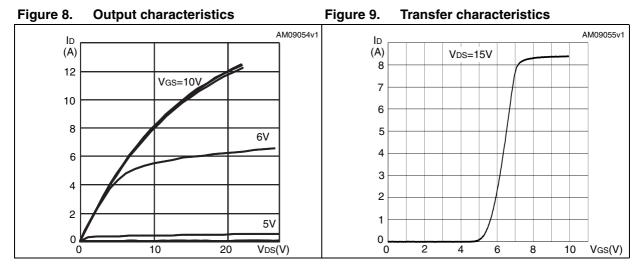




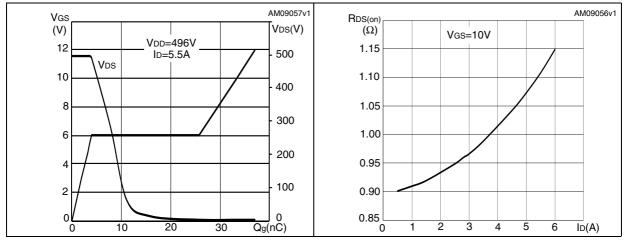


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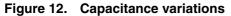


Figure 13. Output capacitance stored energy

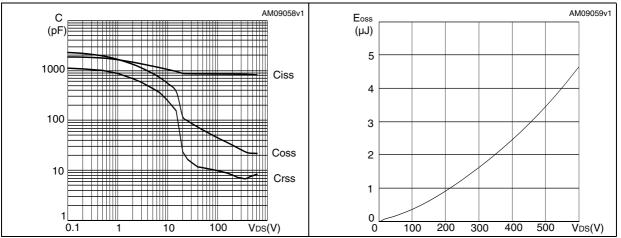


Figure 14. Normalized gate threshold voltage Figure 15. Normalized on-resistance vs vs temperature temperature

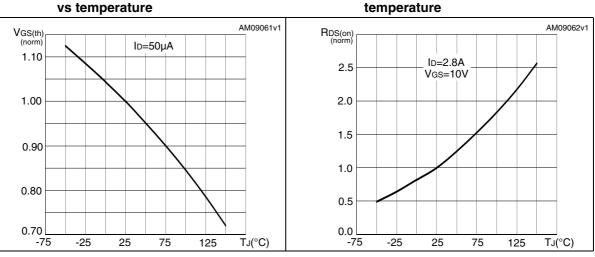


Figure 16. Normalized B_{VDSS} vs temperature

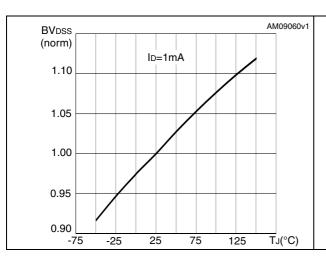
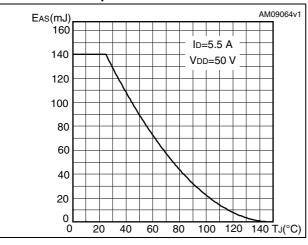
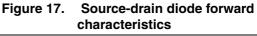
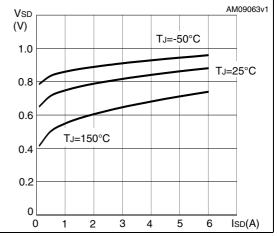


Figure 18. Maximum avalanche energy vs temperature

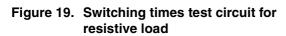


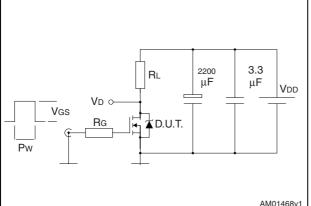






3 Test circuits





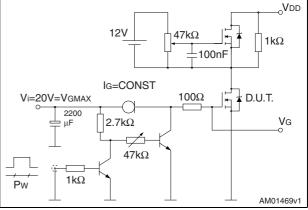
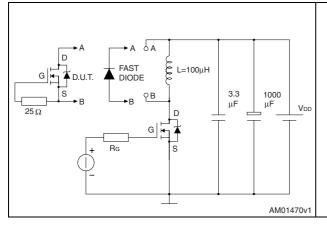


Figure 22. Unclamped Inductive load test

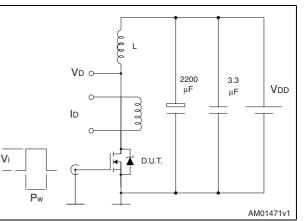
circuit

Figure 20. Gate charge test circuit

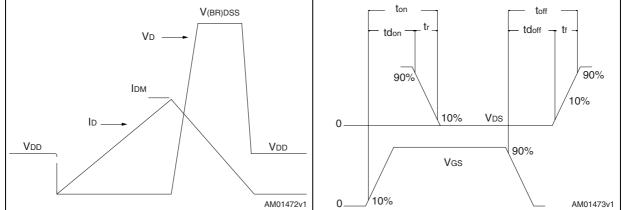
Figure 21. Test circuit for inductive load switching and diode recovery times













4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Dim.	mm			
	Min.	Тур.	Max.	
А	4.4		4.6	
В	2.5		2.7	
D	2.5		2.75	
E	0.45		0.7	
F	0.75		1	
F1	1.15		1.70	
F2	1.15		1.70	
G	4.95		5.2	
G1	2.4		2.7	
Н	10		10.4	
L2		16		
L3	28.6		30.6	
L4	9.8		10.6	
L5	2.9		3.6	
L6	15.9		16.4	
L7	9		9.3	
Dia	3		3.2	

Table 9. TO-220FP mechanical data





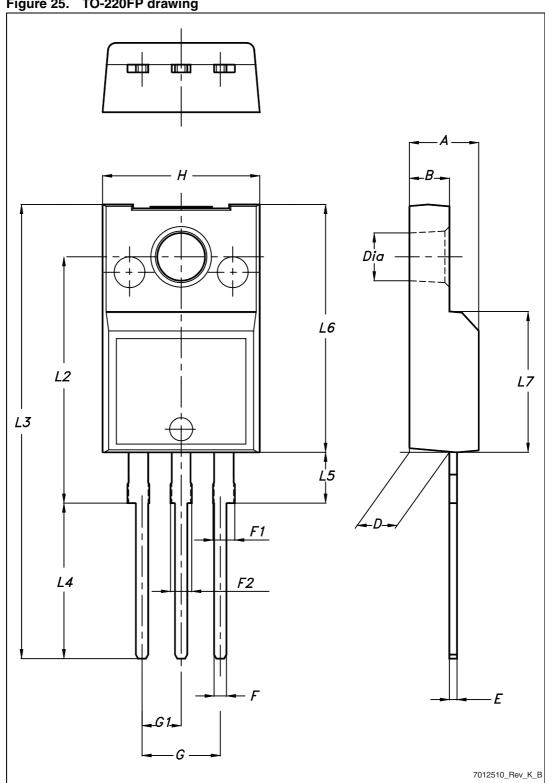


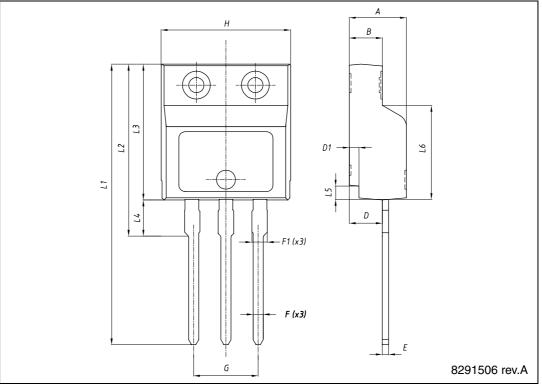
Figure 25. TO-220FP drawing



Dim.				
	Min.	Тур.	Max.	
А	4.40		4.60	
В	2.50		2.70	
D	2.50		2.75	
D1	0.65		0.85	
E	0.45		0.70	
F	0.75		1.00	
F1			1.20	
G	4.95	-	5.20	
Н	10.00		10.40	
L1	21.00		23.00	
L2	13.20		14.10	
L3	10.55		10.85	
L4	2.70		3.20	
L5	0.85		1.25	
L6	7.30		7.50	

 Table 10.
 I²PAKFP (TO-281) mechanical data

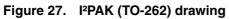
Figure 26. I²PAKFP (TO-281) drawing

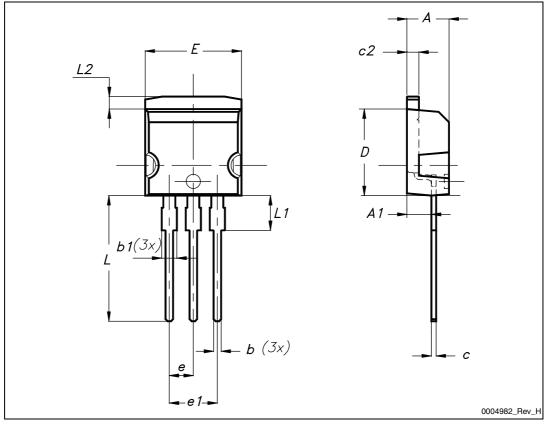




DIM	mm.		
DIM.	min.	typ	max.
А	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
с	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
е	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

Table 11. I²PAK (TO-262) mechanical data







Dim	mm		
Dim.	Min.	Тур.	Max.
Α	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
с	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
е	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20	6.20 6.	
J1	2.40 2		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØР	3.75		3.85
Q	2.65		2.95

Table 12. TO-220 type A mechanical data





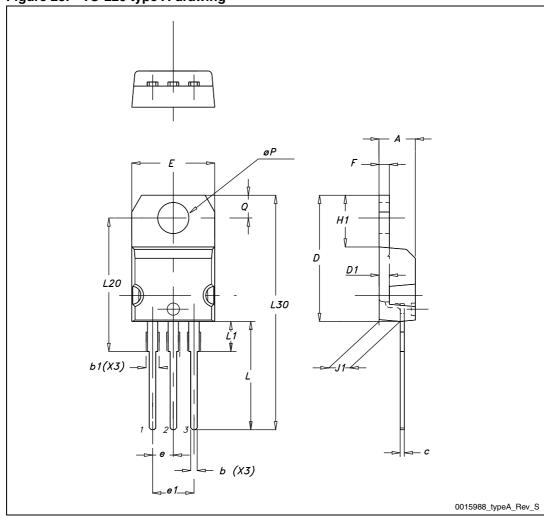


Figure 28. TO-220 type A drawing

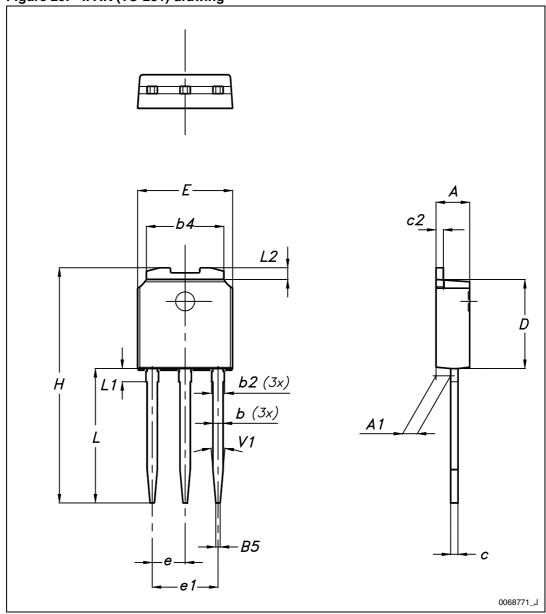


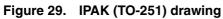
DIM		mm.	
DIM	min.	typ.	max.
А	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
С	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
е		2.28	
e1	4.40		4.60
Н		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

Table 13. IPAK (TO-251) mechanical data











Revision history 5

Table 14.	Document	revision	history
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Date	Revision	Changes
19-May-2006	1	First release.
02-May-2011	2	R _G value has been updated.
06-Dec-2011	3	Removed p/n STD6N62K3 in DPAK.
03-Aug-2012	4	Added package, mechanical data: I ² PAKFP Updated <i>Table 1: Device summary, Table 2: Absolute maximum</i> <i>ratings, Table 3: Thermal data, Table 4: On /off states, Table 13: IPAK</i> (<i>TO-251</i>) <i>mechanical data</i> and <i>Figure 29: IPAK (TO-251) drawing</i> Minor text changes.



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